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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/817,212	KLEIMAN ET AL.	
Examiner	Art Unit	
Than Nguyen	2187	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
WEST Inventor IEEE PALM		6/20/2007	NT∨
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